## Amendments to the Specification:

Please replace paragraph [189] with the following amended paragraph:

[0189] It is recognized in accordance with the invention that the mechanical characteristics of the fabricated structure can vary from fabrication run to run due, e.g., drift in fabrication process parameters and material properties. It is therefore preferred in accordance with the invention that the force-displacement characteristics of the fabricated structure be determined to verify its expected operation. In Oone particularly well-suited characterization technique is described in copending U.S. patent application entitled, "Characterization of Microstructure Force Displacement Behavior," filed on even day herewith, the entirety of which is hereby incorporated by reference. In this technique, deflection of the fabricated structure in the plane of the substrate is transmitted to a compliant reference structure for measurement by displacement sensors. The compliant reference structure is calibrated such that the displacement measurement enables a determination of the corresponding force of the fabricated structure.